

DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited. DESC FORM 193 MAY 86

1.2 <u>Part number</u> . The complete part n 5962-86724	umber snai 01	греа	s snown in t	ne tollow	ng exampre	•	
	e type		Case outline	 	ead finish		
(1. 1.2.1 Device type. The device type s	2.1) hall ident	ify th	(1.2.2) e circuit fu	nction as	MIL_M-3851	0	
Device type Generic n			Circuit func				
01 25524	 Ю Ос	tal in	verting thre	e-state b	uffers		
1.2.2 <u>Case outlines</u> . The case outlin llows:	es shall b	e as d	esignated in	appendi x	C of MIL-M	-38510, an	d as
Outline letter			Cas	e outline			
R		D-8	(20 lead 1/4	" x 1-1/1	6"), dual-i	n-line pac	kage
S		F-9	(20 lead 1/4	" x 1/2")	, flat pack	age	
1.3 Absolute maximum ratings.							
Supply voltage range Input voltage range Storage temperature range Maximum power dissipation (P _D) 1/ Lead temperature (soldering, 10 s Thermal resistance, junction-to-c Case R Case S	econds) - ase (θ _{JC}):		-0.5 V dc t -1.5 V dc t -65 C to +1 2.1 W +300 C 25 C/W 20 C/W +150 C -30 mA to + +30 mA	o 7.0 V d 50°C			
1.4 <u>Recommended operating conditions</u> .							
Supply voltage (V _{CC}) Minimum high-level input voltage Maximum low-level input voltage (Ambient operating temperature ran	(V _{IH})		+4.5 V dc t 2.0 V dc 0.8 V dc -55 C to +1		dc maximum		
Must withstand the added P_D due to s				- 			
MILITARY DRAWING	SIZE		10ent. no. 4933	DWG NO	5. 5962-86724		
DEFENSE ELECTRONICS SUPPLY CENTER				1			

2. APPLICABLE DOCUMENTS

2.1 <u>Government specification and standard</u>. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510

- Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Truth table. The truth table shall be as specified on figure 2.

3.2.3 Logic diagram. The logic diagram shall be as specified on figure 3.

3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.2.5 Switching waveforms. The switching waveforms shall be as specified on figure 4.

3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended ambient operating temperature range.

3.4 <u>Marking</u>. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

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Task	[Sumbal	1		aditions	Group A	Limi	ts	Unit
Test	Symibo] 	l l l	-55°C a inless otha	onditions TA < +125°C Trwise specified	subgroups	Min Limi	Max its	
High level output voltage	 V _{OH} 	VTN.	= +4.5 V = 0.8 V or = V _{2G} = 0 = -3.0 mA	~ 2.0 V 8 V	1,2,3	2.4		V
		IVTN.	= +4.5 V = 0.8 V or = $V_{2G} = 0.20$ = -12.0 m/	2.0 V 5 V	1,2,3	2.0		V
Low level output voltage	V _{OL}	VTN.	= +4.5 V = 0.8 V or = 48.0 mA	- 2.0 V	1,2,3		0.55	۷
Hysteresis (VT+ - VT-)	Vhyst	Vcc	= +4.5 V		1,2,3	0.2		V
Input clamp voltage	VIC	VCC IIN	= +4.5 V = -18 mA		1,2,3		-1.2	v
High level input current	I IH1	V _{CC} VIN	= +5.5 V = 2.7 V		1,2,3		50	μΑ
	I IH2	V _{CC} VIN	= +5.5 V = 5.5 V		1,2,3		1.0	mA
Low level input current	IIL	Vcc	= +5.5 V = 0.5 V	Any A	1,2,3		-0.4	mA
		*1N	- 0.0 (Any G		 	-2.0	İ İ
Output short circuit current	Ios	VCC VOUT	= +5.5 V r = 0 V		1,2,3	-50.0	-225.0	mA
Off-state current	I IOZH	V V VOUT	= +5.5 V r = 2.4		1,2,3		50.0	μA
	IOZL	V V V OUT	≖ +5.5 ¥ Γ = 0.5		1,2,3		-50.0	μA
See footnotes at end of tabl	e.	<u> </u>				<u> </u>	<u> </u>	·
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Test	Symbol		onditions	Group A	Limi	ts	Un
iest		-55°C unless oth	<pre>< T_A < +125°C erwise specifie</pre>	Isubgroup	s Min Limi	Max ts	Ť
Supply current	ICC	V _{CC} = +5.5 V	All_outputs op IG = 0.0 V 2G = 0.0 V Data = 0.0 V	oen 1,2,3		65	m/
		V _{CC} = +5.5 V	All outputs lo IG = 0.0 V 2G = 0.0 V Data = 3.0 V			90	m/
		$V_{CC} = +5.5 V$	Al <u>l</u> outputs HJ 1G = 3.0 V 2G = 3.0 V Data = 0.0 V	1		105	m/
Functional testing		See 4.3.1c		7,8			
Propagation delay from Al to Yl	tpLH	$C_{L} = 50 \text{ pF}$ $R_{L1} = 1 \text{ k}\Omega$	2/	9		7	n:
		$\begin{bmatrix} R_{L2}^{L1} = 90\Omega \\ \end{bmatrix}$	3/	9,10,11		9	
	tPHL		2/	9		7	l ns
			<u>3</u> /	9,10,11		9	
Propagation delay from output enable to Y1	tpzh		2/	9		10	ns
			<u>3</u> /	9,10,11		13	
	tpzl		<u>2</u> /	9		15	n:
			<u>3</u> /	9,10,11	 	18	
See footnotes at end of tab	ole.						
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Test		Condi	tions	Group A	p A		Unit
		-55°C < TA unless otherwi	<pre>< +125°C se specified</pre>	subgroups	Min Limi	Max ts	T I I
ropagation delay from output enable to Yl	t _{PHZ1}	$R_{L1} = 1 k\Omega$ $R_{L2} = 90\Omega$	C _L = 50 pF <u>2</u> /	9		18	ns
			 C _L = 5 pF <u>3</u> /	9,10,11		12	
	tpLZ1		C _L = 50 pF <u>2</u> /	9		18	ns
		-	C _L = 5 pF <u>3</u> /	9,10,11		18	
Propagation delay from output enable to Y1	t _{PHZ2}	$C_{L} = 5 \text{ pF}$ $R_{L1} = 1 \text{ k}\Omega$ $R_{L2} = 90\Omega$		9		9	ns
	tpLZ2			9		15	ns
1/ Not more than one of condition should no 2/ V _{CC} = 5.0 V. 3/ V _{CC} = 4.5 V to 5.5	t exceed o	ld be shorted at a	a time and the du	ration of t	ne short	: circui	
$\frac{2}{V_{CC}} = 5.0 \text{ V}.$	t exceed o	ld be shorted at a	a time and the du	ration of t	ne short	: circui	t
condition should no 2/ V _{CC} = 5.0 V. <u>3</u> / V _{CC} = 4.5 V to 5.5	V.	ne second.	ODE IDENT. NO.	DWG NO.	ne short	: circui	t
$\frac{2}{V_{CC}} = 5.0 \text{ V}.$	V. AWING UPPLY CENT	ne second. SIZE C A	· · ·	DWG NO.	ne short 2-86724	: circui	t

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3.5 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.6 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

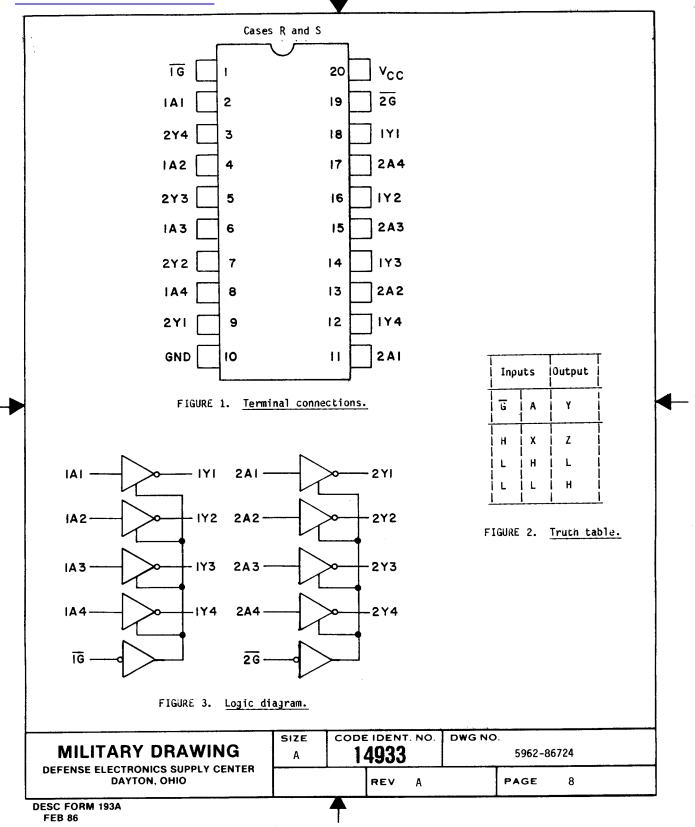
- a. Burn-in test (method 1015 of MIL-STD-883).
 - (1) Test condition A, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

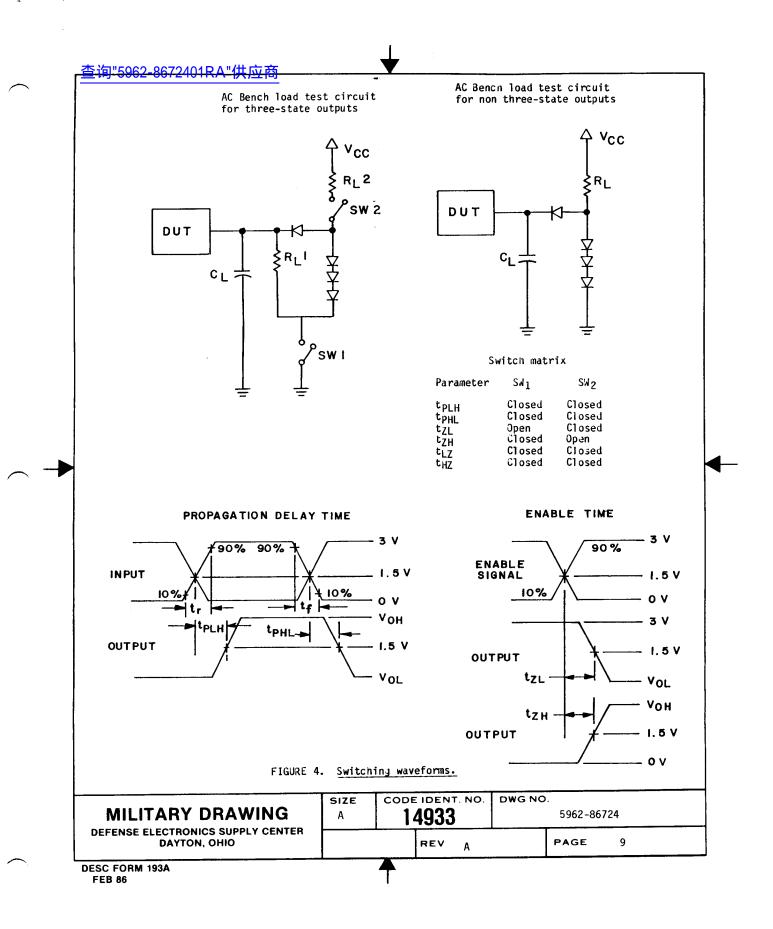
4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

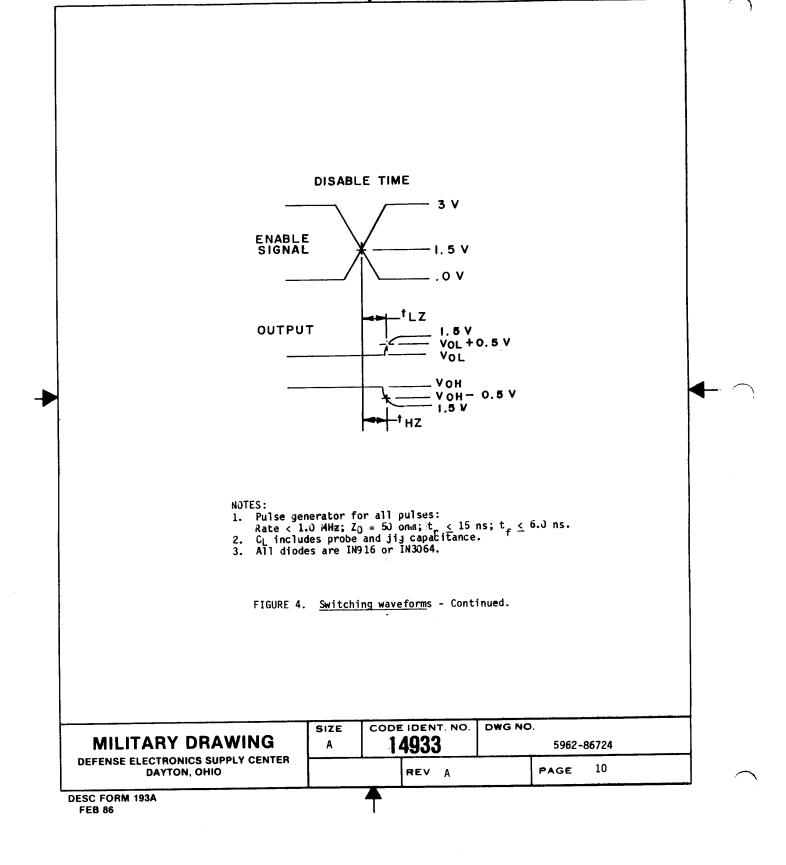
4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroups 7 and 8 shall verify the truth table.
- 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
 - Test condition A, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

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查询"5962-8672401RA"供应商MBLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups - (per method 5005, table I)
Interim electrical parameters (method 5004)	
[Final electrical test parameters (method 5004)	1*, 2, 3, 7, 8, 9, 10, 11
Group A test requirements (method 5005)	1, 2, 3, 7, 8, 9, 10**, 11**
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

* PDA applies to subgroup 1.

** Subgroups 10 and 11, if not tested, shall be guaranteed to the limits specified in table I.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 <u>Comments</u>. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 <u>Approved source of supply</u>. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

 Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1</u> /
5962-8672401RX	34335	AM25S240/BRA
5962-8672401SX	34335	AM255240/BSA

 $\frac{1}{1}$ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

34335

Vendor name and address

Advanced Micro Devices, Inc. 901 Thompson Place P.O. Box 3453 Sunnyvale, CA 94088

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